

Issue Classification			Application/Control No.		Applicant(s)/Patent under Reexamination	
			09/535,457		BAIJ, FRED CHRISTIAN	
Examiner			Art Unit			
Chi Q. Nguyen			3635			

ISSUE CLASSIFICATION			
ORIGINAL		CROSS REFERENCE(S)	
CLASS	SUBCLASS	CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)
52	105	52	243 481.1
INTERNATIONAL CLASSIFICATION			
E	0	4	B 1/00
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			/

Chi Q. Nguyen 9/29/2006
(Assistant Examiner) (Date)

Tonya M(Bridge 10/6/06
(Legal Instruments Examiner) (Date)

NAOKO SLACK
SUPERVISORY PATENT EXAMINER
TECHNOLOGY CENTER 3600
(Primary Examiner) (Date)
9/30/06

Total Claims Allowed: 12

O.G. Print Claim(s)	O.G. Print Fig.
1	5

<input type="checkbox"/> Claims renumbered in the same order as presented by applicant		<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R. 1.47	
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